



CLUSTER DETECTOR TEST REPORT

CLUSTER DETECTOR No. 07
Test carried on 09.01.12 – 10.01.12

Ch.	HEX	U _{op} [V]	U _{op} – 500 V		U _{op}			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{WFHM}$	Pos. [Ch.]	FWHM [keV]
A	148	4000	2.06	n.c.	2.06	n.c.	6138	
B	143	4000	1.91	n.c.	1.90	n.c.	6028	
C	69	4500	2.09	n.c.	1.92	n.c.	9622	
D	30	4000	2.01	n.c.	1.94	n.c.	6997	
E	82	4000	2.13	n.c.	2.00	n.c.	5970	
F	73	4000	2.06	n.c.	2.04	n.c.	6238	
G	76	4000	2.04	n.c.	2.04	n.c.	5790	

Operational Temperature: -165.7 °C

Date: 10.02.2012

Tested by:
/I.Kojouharov/

Assembly and test remarks:

Regular Test after assembly at RIKEN

Test Equipment:

HV – ORTEC 660

Main Amplifier – ORTEC 671, $\tau = 6 \mu\text{s}$, Gain 100 x 0.72

ADC – 4801A (RIKEN), MCA - PC98B

Source - ^{60}Co